

Substitute Form PTO-1449
(Modified)U.S. Department of Commerce
Patent and Trademark OfficeAttorney's Docket No.
09712-333001Application No.
10/659,103**Information Disclosure Statement
by Applicant**

(Use several sheets if necessary)

(37 CFR 1.98(b))

Applicant
Henry A. HillFiling Date
September 9, 2003Group Art Unit
1656**U.S. Patent Documents**

| Examiner Initial | Desig. ID | Document Number | Publication Date | Patentee | Class | Subclass | Filing Date If Appropriate |
|------------------|-----------|------------------|------------------|---------------------|-------|----------|----------------------------|
| SAT | AA | US 2003/009067 5 | 05/15/03 | Fujiwara | | | |
| ↑ | AB | US 2002/008967 1 | 07/11/02 | Hill | | | |
| | AC | US 2001/003595 9 | 11/01/01 | Hill | | | |
| | AD | 6,330,105 | 12/11/01 | Rozelle et al. | | | |
| | AE | 6,304,318 | 10/16/01 | Matsumoto | | | |
| | AF | 6,252,668 | 06/26/01 | Hill | | | |
| | AG | 6,246,481 | 06/12/01 | Hill | | | |
| | AH | 6,236,507 | 05/22/01 | Hill et al. | | | |
| | AI | 6,181,420 | 01/30/01 | Badami et al. | | | |
| | AJ | 6,159,644 | 12/12/00 | Hidetoshi | | | |
| | AK | 6,134,007 | 10/17/00 | Naraki et al. | | | |
| | AL | 6,046,792 | 04/04/00 | Van Der Werf et al. | | | |
| | AM | 6,040,096 | 03/21/00 | Kakizaki | | | |
| | AN | 6,020,964 | 02/01/00 | Loopstra et al. | | | |
| | AO | 6,008,902 | 12/28/99 | Rinn | | | |
| | AP | 5,801,832 | 09/01/98 | Van Der Brink | | | |
| | AQ | 5,781,277 | 07/14/98 | Iwamoto | | | |
| | AR | 5,757,489 | 05/26/98 | Kawakami | | | |
| | AS | 5,757,160 | 05/26/98 | Kreuzer | | | |
| | AT | 5,764,361 | 06/09/98 | Kato et al. | | | |
| | AU | 5,724,136 | 03/03/98 | Zanoni | | | |
| | AV | 5,663,893 | 09/02/97 | Wampler et al. | | | |
| | AW | 5,663,793 | 09/02/97 | de Groot | | | |
| ↓ | AX | 5,491,550 | 02/13/96 | Dabbs | | | |
| SAT | AY | 5,408,318 | 04/18/95 | Slater | | | |

Examiner Signature

S.A. Taven

Date Considered

12-7-05

EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

| | | | |
|---|--|---------------------------------------|-------------------------------|
| Substitute Form PTO-1449 (Modified) | U.S. Department of Commerce Patent and Trademark Office | Attorney's Docket No. 09712-333001 | Application No. 10/659,103 |
| Information Disclosure Statement by Applicant (Use several sheets if necessary) | | Applicant Henry A. Hill | |
| | | Filing Date September 9, 2003 | Group Art Unit 1656 |
| (37 CFR §1.98(b)) | | | |

| U.S. Patent Documents | | | | | | | |
|-----------------------|-----------|-----------------|------------------|-----------------|-------|----------|----------------------------|
| Examiner Initial | Desig. ID | Document Number | Publication Date | Patentee | Class | Subclass | Filing Date If Appropriate |
| SAT | AZ | 5,187,543 | 02/16/93 | Ebert | | | |
| ↑ | AAA | 5,151,749 | 09/29/92 | Tanimoto et al. | | | |
| | ABB | 5,114,234 | 05/19/92 | Otsuka et al. | | | |
| | ACC | 5,064,289 | 11/12/91 | Bockman | | | |
| | ADD | 4,881,816 | 11/21/89 | Zanoni | | | |
| | AEE | 4,859,066 | 08/22/89 | Sommargren | | | |
| | AFF | 4,802,765 | 02/07/89 | Young et al. | | | |
| | AGG | 4,790,651 | 12/13/88 | Brown et al. | | | |
| | AHH | 4,711,573 | 12/08/87 | Wijntjes et al. | | | |
| | AII | 4,662,750 | 05/07/87 | Barger | | | |
| SAT | AJJ | 4,606,638 | 08/19/86 | Sommargren | | | |

| Foreign Patent Documents or Published Foreign Patent Applications | | | | | | | | |
|---|-----------|--|------------------|--------------------------|-------|----------|-------------|----|
| Examiner Initial | Desig. ID | Document Number | Publication Date | Country or Patent Office | Class | Subclass | Translation | |
| | | | | | | | Yes | No |
| SAT | AKK | WO 01/90686 | 11/29/01 | WIPO | | | | |
| SAT | ALL | JP 10-260009 Translation of Abstract Only | 09/29/98 | Japan | | | X | |
| SAT | AMM | JP 7-351078 | 12/25/95 | Japan | | | | |
| SAT | ANN | JP 8-117083 Abstract Only | 04/15/96 | Japan | | | X | |
| — | AOO | JP 9-178415 Translation of Abstract Only | 07/11/97 | Japan | | | X | |
| — | APP | JP 9-280822 Translation of Abstract Only | 10/31/97 | Japan | | | X | |

Other Documents (include Author, Title, Date, and Place of Publication)

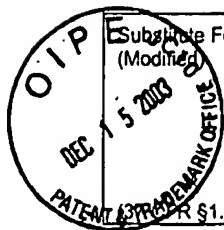
| | |
|--|----------------------------|
| Examiner Signature <i>S.A. Turner</i> | Date Considered 12-7-05 |
| EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. | |

| | | | |
|--|--|---------------------------------------|-------------------------------|
| Substitute Form PTO-1449 (Modified) | U.S. Department of Commerce Patent and Trademark Office | Attorney's Docket No. 09712-333001 | Application No. 10/659,103 |
| Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b)) | | Applicant Henry A. Hill | |
| | | Filing Date September 9, 2003 | Group Art Unit 1656 |

| Examiner Initial | Desig. ID | Document |
|---------------------|--------------|--|
| SAT | AQQ | Bennett, S.J. . "A Double-Passed Michelson Interferometer." Optics Communications, 4:6, pp. 428-430, 1972. |
| SAT | ARR | Wu et al. "Analytical modeling of the periodic nonlinearity in heterodyne interferometry." Applied Optics, 37:28, pp. 6696-6700, 1998. |
| SAT | ASS | Hines et al. "Sub-Nonometer Laser Metrology - Some Techniques and Models. ESO Conference on High-Resolution Imaging by Interferometry II, pp.1195-1204, 1991 |
| SAT | ATT | Bobroff, Norman. "Recent advances in displacement measuring interferometry." Meas. Sci. Technol. 4, pp. 907-926, 1993. |
| SAT | AUU | Oka et al. "Polarization heterodyne interferometry using another local oscillator beam." Optics Communications, 92, pp. 1-5, 1992. |
| SAT | AVV | Badami et al. "Investigation of NonLinearity in High Accuracy Heterodyne Laser Interferometry." American Society for Precision Engineering, 1997 Proceedings, 16, pp. 153-156, 1997. |
| SAT | AWW | Bobroff, Norman. "Residual errors in laser interferometry from air turbulence and nonlinearity." Applied Optics, 26:13, pp. 2676-2686, 1987. |

| | |
|--|-----------------------------------|
| Examiner Signature <i>S.A. Turner</i> | Date Considered <i>12-7-05</i> |
| EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. | |

From
10/360,364


 Substitute Form PTO-1449
 (Modified)

 U.S. Department of Commerce
 Patent and Trademark Office

 Attorney's Docket No.
 09712-333001

 Application No.
 10/659,103

**Information Disclosure Statement
 by Applicant**

(Use several sheets if necessary)

 Applicant
 Henry A. Hill

 Filing Date
 September 9, 2003

Group Art Unit

U.S. Patent Documents

| Examiner Initial | Desig. ID | Document Number | Publication Date | Patentee | Class | Subclass | Filing Date If Appropriate |
|------------------|-----------|-----------------|------------------|----------|-------|----------------|----------------------------|
| SAT | AA | 5,363,196 | 11/08/1994 | Cameron | 356 | 358 | |
| SAT | AB | 5,790,253 | 08/04/1998 | Kamiya | 356 | 363 | |
| SAT | AC | 6,137,574 | 10/24/2000 | Hill | 356 | 351 | |
| | AD | | | | | | |
| | AE | | | | | | |
| | AF | | | | | | |
| | AG | | | | | | |
| | AH | | | | | | |
| | AI | | | | | | |
| | AJ | | | | | | |
| | AK | | | | | | |

Foreign Patent Documents or Published Foreign Patent Applications

| Examiner Initial | Desig. ID | Document Number | Publication Date | Country or Patent Office | Class | Subclass | Translation | |
|------------------|-----------|-----------------|------------------|--------------------------|-------|----------|-------------|----|
| | | | | | | | Yes | No |
| | AL | | | | | | | |
| | AM | | | | | | | |
| | AN | | | | | | | |
| | AO | | | | | | | |
| | AP | | | | | | | |

Other Documents (include Author, Title, Date, and Place of Publication)

| Examiner Initial | Desig. ID | Document |
|------------------|-----------|----------|
| | AQ | |
| | AR | |
| | AS | |
| | AT | |

Examiner Signature

S.A. TUNGA

Date Considered

12-7-05

EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.